

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KLUBEK ET AL.	
		Examiner Dawn Garrett	Art Unit 1774	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0004215	01-2004	Iechi et al.	257/40
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2000260565	09-2000	Japan	Takahashi et al.	----
	O	JP 2000021574	01-2000	Japan	Ueno et al.	----
	P					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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